



A broad introduction to the collection and analysis of x-ray absorption fine structure (XAFS) data

Location

Argonne National Laboratory
Advanced Photon Source
Argonne, IL 60439

Instructors

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Abstract

The 2009 APS XAFS School includes classroom lectures delivered by leading experts in the field, and hands-on instruction in sample preparation, data collection, and data processing and analysis using FEFF, IFEFFIT, and ATHENA and ARTEMIS.

Participants will collect XAFS data from a variety of samples during two days of beam time at six APS spectroscopy beamlines, then learn to analyze the data during data analysis laboratories.

The lectures cover the basic physics of x-ray absorption and XAFS theory, best practices in XAFS sample preparation and data collection, and basic principles of data analysis.

Web Page

http://xafs.org/Workshops/APS2009

Important Dates

May 11 — Last day to apply for the course

May 18 — Acceptance letters sent by e-mail





